

Sale

Instrument Name: **ToF-SIMS**

Manufacturer: **Physical Electronics Inc (PHI)**

Model: **TRIFT III**

Manufacturer Year: **2000**

- Ga ion primary beam source
- Ar/O₂ gas sputter gun
- High mass resolution mass spectrum
- High lateral resolution elemental mapping
- High resolution depth profiling
- Excellent working condition



Interest? Contact:

Dr. Xinqi Chen

Ph: 847-491-5505

Email: xchen@northwestern.edu